

METALBEAMS WORKSHOP

This is MAX IV !

Aymeric ROBERT

Scientific Director – Physical Sciences



NOV 2023

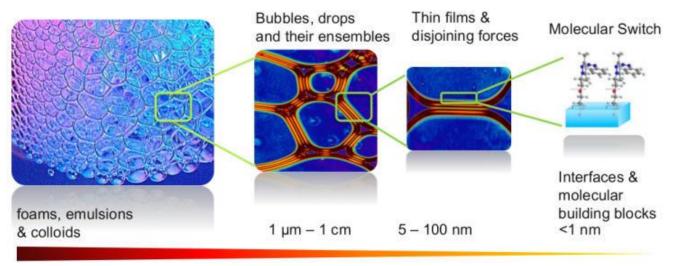


MAX IV - A nearly diffraction-limited synchrotron source

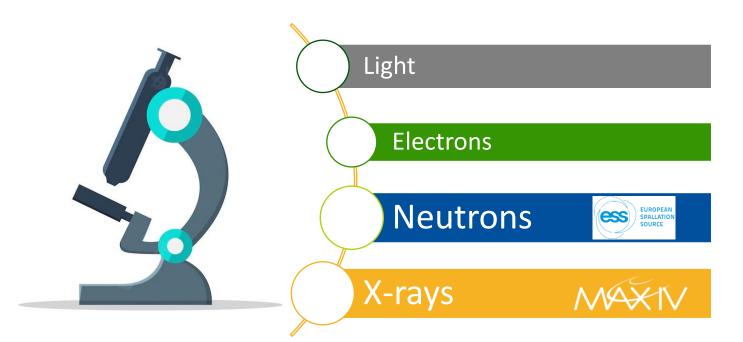
Examples from our Science Programme



Understanding the structure and dynamics of matter

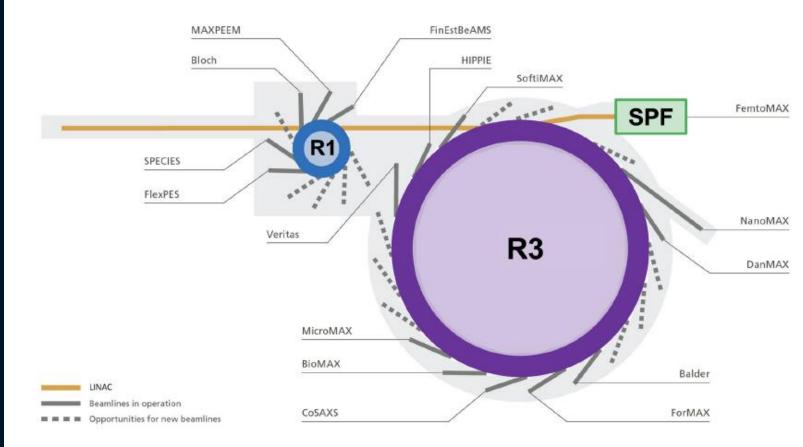


https://www.uni-muenster.de/SON/en/research/nanomaterials/b4.html





www.maxiv.lu.se



Our X-ray Sources

3 Accelerators

Linac – Linear AcceleratorR1 - 1.5GeV storage ringR3 - 3GeV storage ring

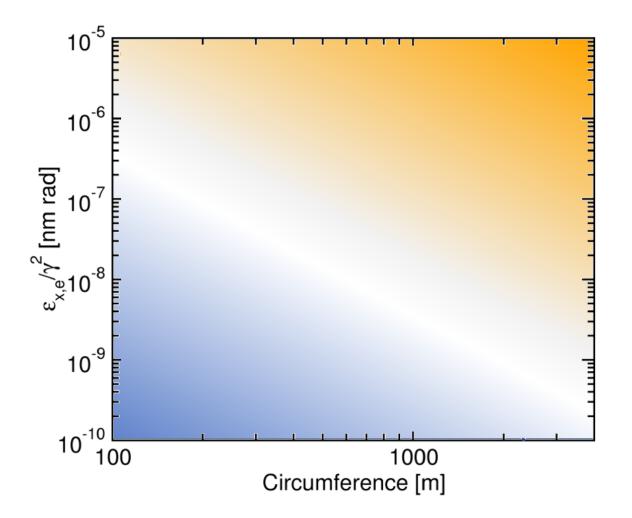


A. Robert et al., "MAX IV Laboratory", Eur. Phys. J. Plus 138, 495 (2023).

• 1.5 GeV Storage Ring

- C = 100m , $\mathcal{E} \sim 6$ nmrad
- Diffraction-limited X-rays at 16 eV
- World-leading source of soft X-rays

- C = 528m , $\mathcal{E} \sim 200-330$ nmrad
- Diffraction-limited X-rays at 300eV
- First 4th generation storage ring

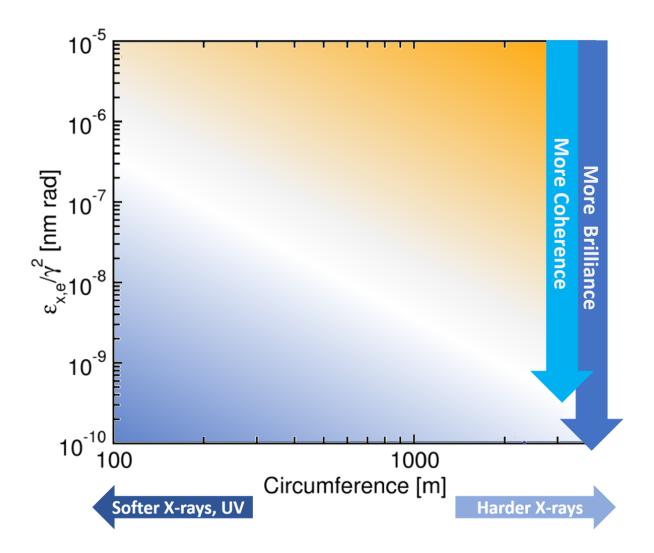




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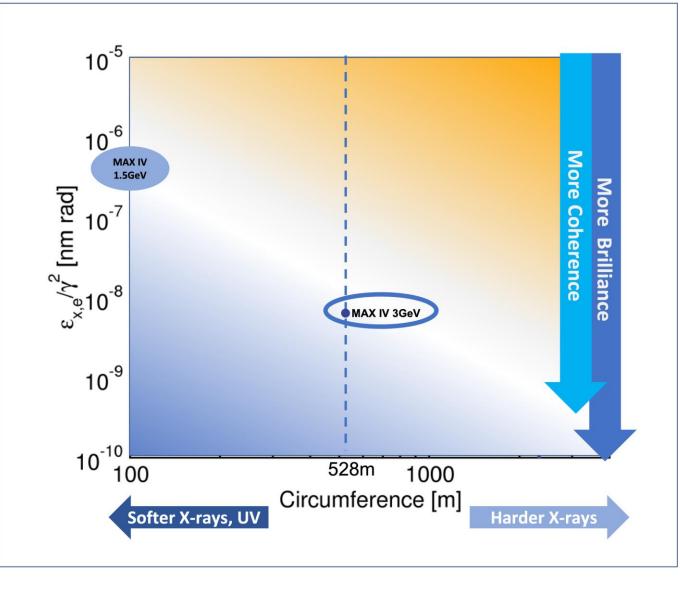




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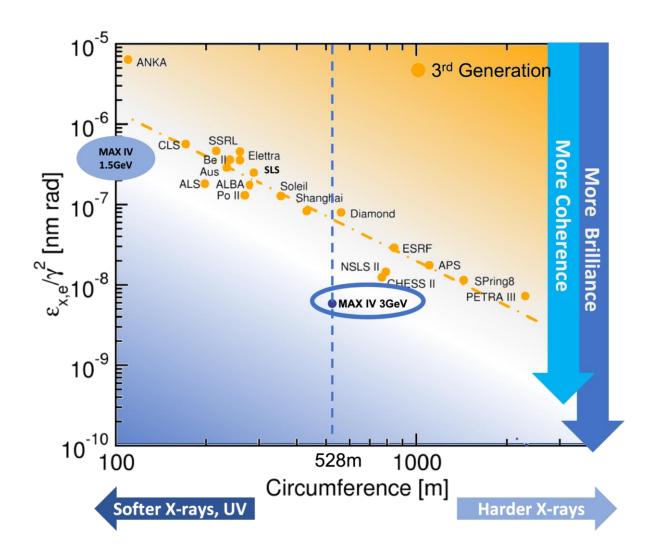




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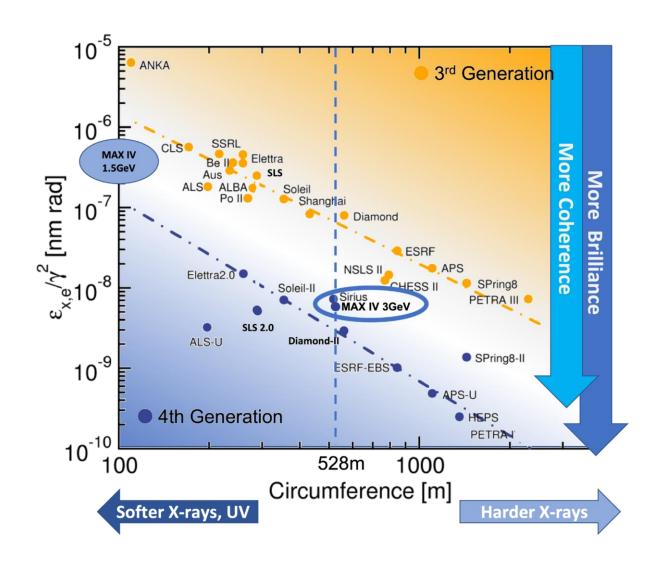




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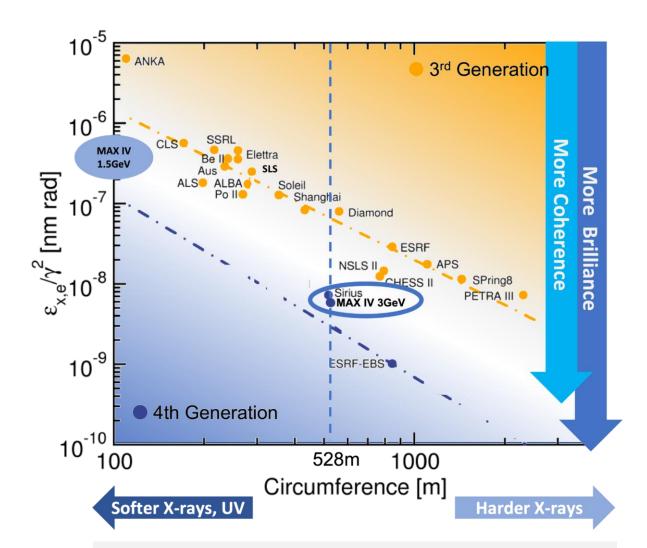


• 1.5 GeV Storage Ring

- C = 100m , $\mathcal{E} \sim 6$ nmrad
- Diffraction-limited X-rays at 16 eV
- World-leading source of soft X-rays

• 3 GeV Storage Ring

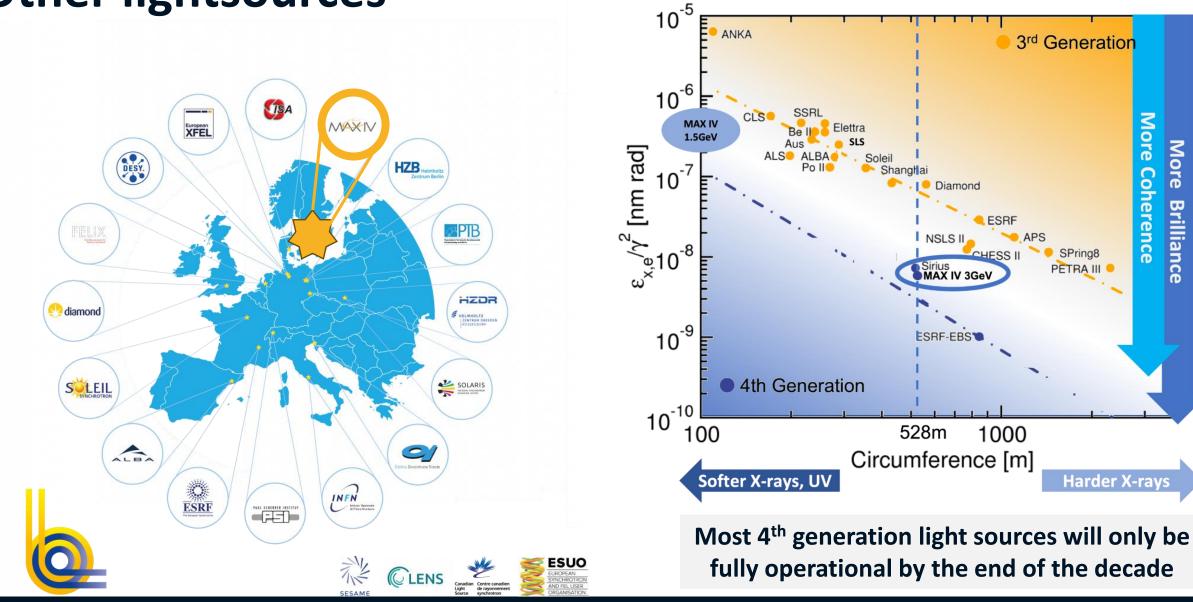
- C = 528m, $\mathcal{E} \sim 200-330$ nmrad
- Diffraction-limited X-rays at 300eV
- First 4th generation storage ring



Most 4th generation light sources will only be fully operational by the end of the decade

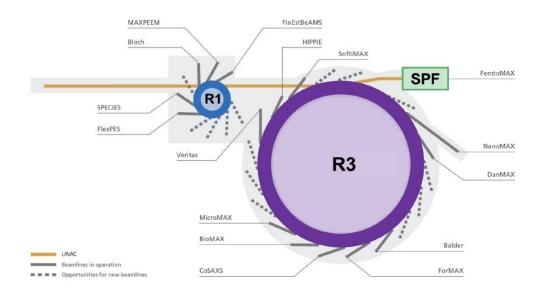


Other lightsources





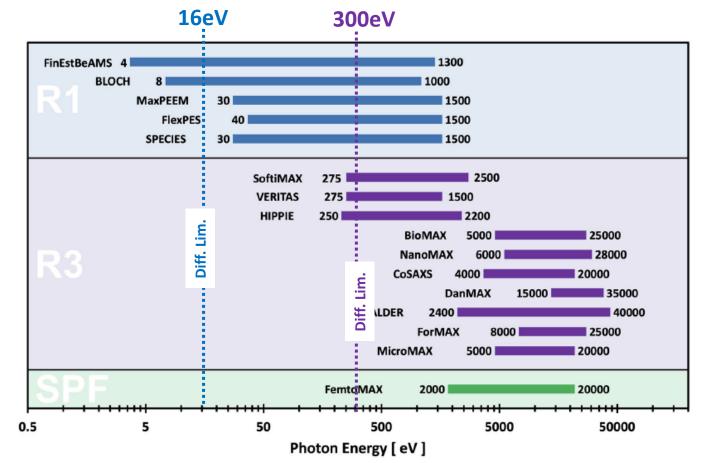
Beamline Portfolio



Soft X-rays surface and sub-surface information

Hard X-rays bulk information and buried interfaces

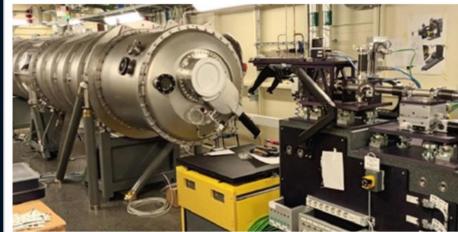
16 beamlines covering a broad X-ray energy range from 4 eV to 40 keV



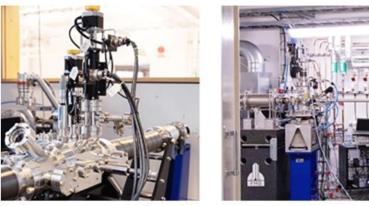
Research conducted at MAX IV, a Swedish national user facility, is supported by the Swedish Research Council under contract 2018-07152, the Swedish Governmental Agency for Innovation Systems under contract 2018-04969, and Formas under contract 2019-02496.





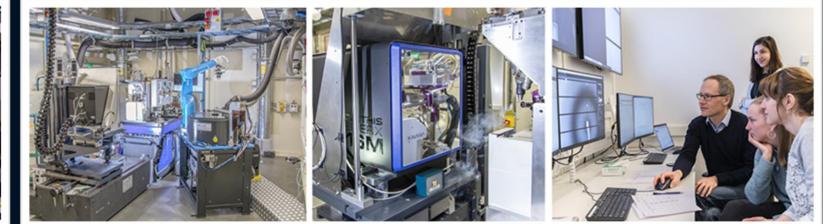


Beamlines



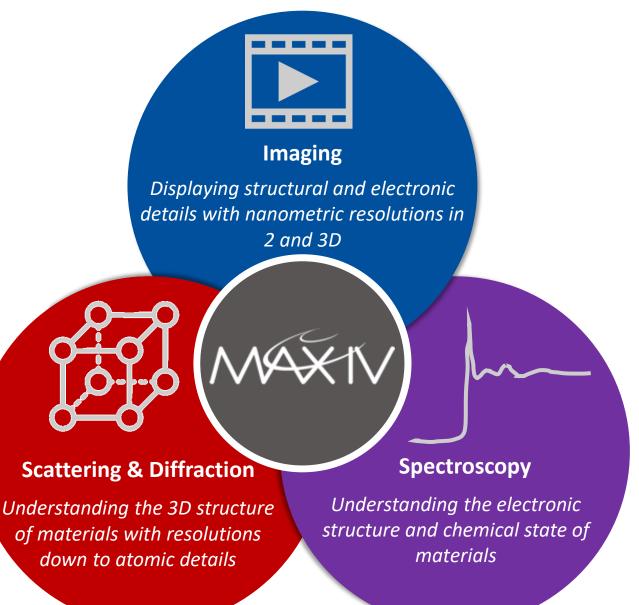




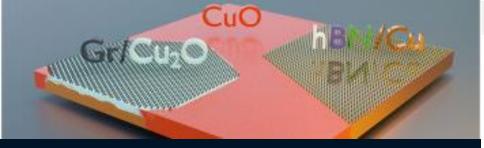


Materials science research with one of the most powerful X-ray User Facility





Measuring electrons (e-) or X-rays photons (ph)



Spectroscopy

Ambient Pressure X-ray photoelectron Spectroscopy

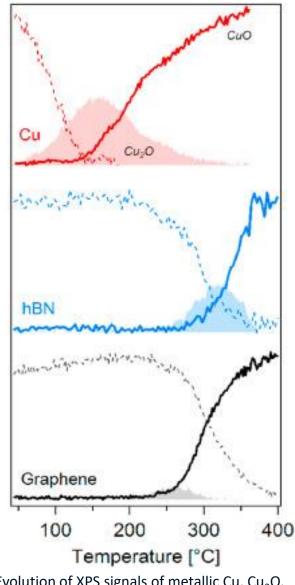
AP-XPS

HIPPIE

Copper oxidation protection with graphene and hexagonal boron nitride

ntensity [arb.un.

- Uncoated copper is oxidized by molecular oxygen to Cu₂O near room temperature
- Both G and h-BN retard the oxidation temperature by 120 °C
- h-BN forms a protective layer preventing intercalation of O₂.
- Protection is effective until the h-BN is rapidly and completely etched away.
- G allows intercalation of O₂ that leads to partial and slow oxidation of Cu to Cu₂O.
- Due to the low rate of O₂ intercalation, no CuO is formed until G is etched.



Evolution of XPS signals of metallic Cu, Cu_2O , and CuO in the presence of 2mbar O_2

M. Scardamaglia et al., CARBON 171 (2021) 610



Spectroscopy

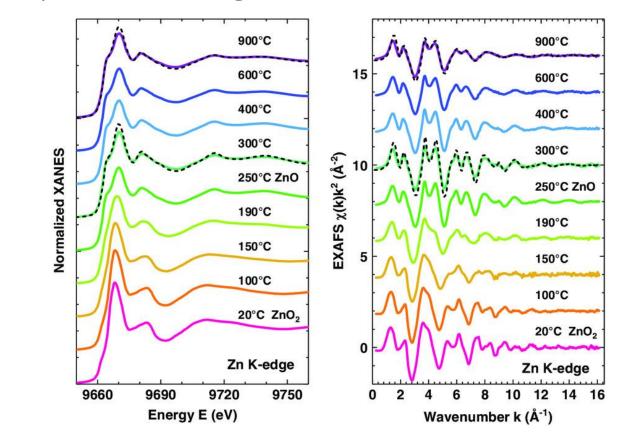
X-ray Emission/Absorption Spectroscopies

> XES - XAS EXAFS





X-ray absorption spectroscopy and X-ray emission spectroscopy are element specific techniques and provide atomic characterization of components, including local structure and electronic state.



In situ experimental Zn K-edge X-ray absorption near edge structure (XANES) and extended X-ray absorption fine structure (EXAFS) spectra obtained in the temperature range of 20–900 °C during the decomposition of ZnO2 to ZnO. The spectra for reference microcrystalline ZnO are shown by dashed lines at 300 and 900 °C for comparison.

In Situ Study of Zinc Peroxide Decomposition to Zinc Oxide by X-Ray Absorption Spectroscopy and Reverse Monte Carlo Simulations, Kuzmin et al., Phys. Status Solidi B **259**, 2300001 (2022)



Imaging

PhotoElectron Emission Microscopy

PEEM





Surface imaging with structural, chemical, electronic, and magnetic contrast with nanometer spatial resolution

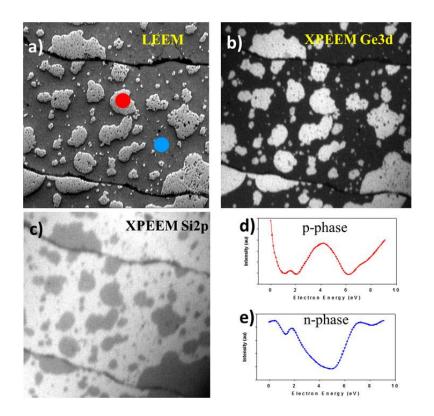
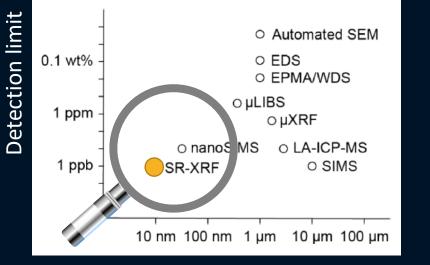


FIGURE 1 The real space characterization of the mixed phase in Ge-intercalated graphene. (A) A LEEM image (electron energy 3.5 eV) showing the islands of the p-doped phase in the sea of the n-doped phase. The height difference between p- and n-doped phases in the LEEM image is emphasized by moving the contrast aperture slightly away from the optimal position. (B) Ge3d XPEEM image of the same area as in (A). The white islands belong to the p-phase that has twice as much germanium compared to the n-phase. Photon energy $h_v = 100$ eV and electron kinetic energy = 64 eV. (C) Si2p XPEEM image showing an extra attenuation of the Si2p photoelectrons going through the p-type islands. Photon energy $h_v = 150$ eV and electron kinetic energy 45.2 eV. Field of view is 10 μ m in all three images. (D,E) LEEM IV curves collected from areas marked by red and blue circles, respectively, in the LEEM image (A) displaying drastic difference in the reflectivity for p- and n-doped Ge-intercalated graphene.

Ambipolar Behavior of Ge-Intercalated Graphene: Interfacial Dynamics and Possible Applications, Zakharov et al., Front. Phys. 9 641168 (2021)



Imaging - SDXM



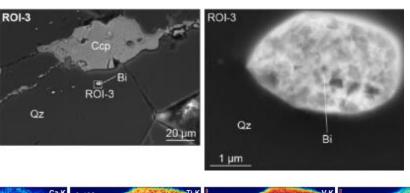
Resolution

SEM: Scanning Electron Microscopy EDS: Energy Dispersive Spectrometry WDS: Wavelength Dispersive Spectrometry LA-ICP-MS: Laser Ablation inductively coupled plasma mass spectrometry XRF: X-ray Fluorescence LIBS: Laser Induced Breakdown Spectroscopy EPMA: Electron Probe Micro-Analyzer SIMS: Secondary Ion Mass Spectrometry

NANOMAX



Investigating droplet-shaped Bismuth grain in a quartz vein with synchrotron radiation high-resolution fluorescence microscopy



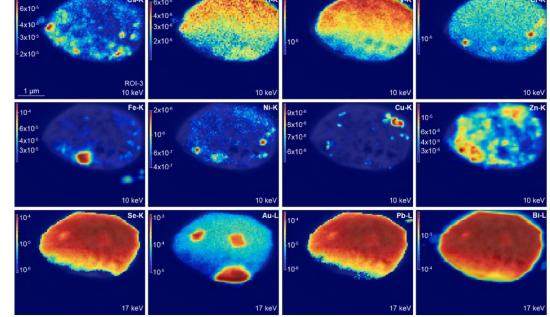


Fig. 10. Selected pseudo-quantitative SR-XFM element fluorescence maps of ROI-3. The scales are based on wt.% concentration but calibrated to an arbitrary set of values. This allows qualitative comparison between element maps. A logarithmic scale was used to better resolve weakly fluorescent features. A cut-off concentration was applied to all maps to separate features from background. Element fluorescence maps Ca-K to Zn-K are from the 10 keV scan, maps Se-K to Bi-L from the 17 keV scan.

Extreme resolution synchrotron X-ray fluorescence mapping of ore samples M. Warlo *et al.*, Ore Geology Reviews **120**, 104620 (2022)



Imaging

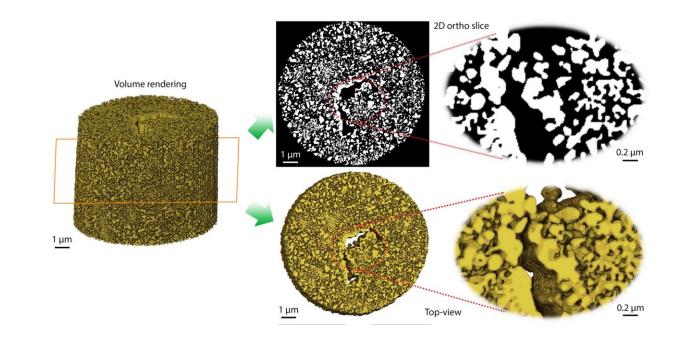
Tomographic Imaging

CT

DANMAX FORMAX NANOMAX



Explore the hard X-ray coherence for high resolution and (hierarchical phase-contrast, full field, micro-, nano-, holo-) 3D computed tomography imaging



3D rendering of hierarchically-structured monolithic nanoporous gold with approx. 23 nm spatial resolution obtained by ptychographic X-ray tomography, showing binary representation of gold and pores after image segmentation (above) and the resulting orthographic projection.

Correlative Multiscale 3D Imaging of a Hierarchical Nanoporous Gold Catalyst by Electron, Ion and X-ray Nanotomography, Fam et al., Chem. Cat. Chem. **10**, 2858 (2018)

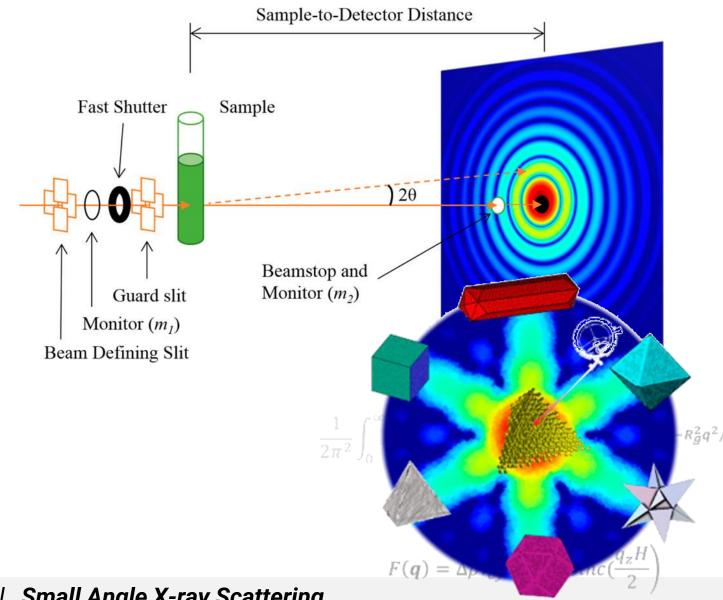


Scattering

Small Angle X-ray Scattering

SAXS

Understanding amorphous and disordered, complex systems with nanometric characteristic lengthscales



COSAXS



Li et al., Small Angle X-ray Scattering for nanoparticle research, Chem. Rev. 16 (18), 11128 (2016)



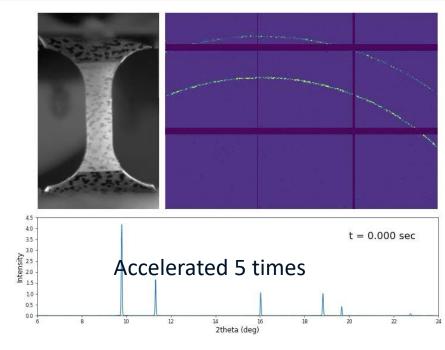
Scattering/Diffraction

X-ray Diffraction

XRD

TRansformation Induced Plasticity (TRIP) steels are used in many applications due to their outstanding combination of strength and ductility

Austenite to martensite phase transition observed at 250Hz







M. Hokka et al., Tampere U. (Finland)



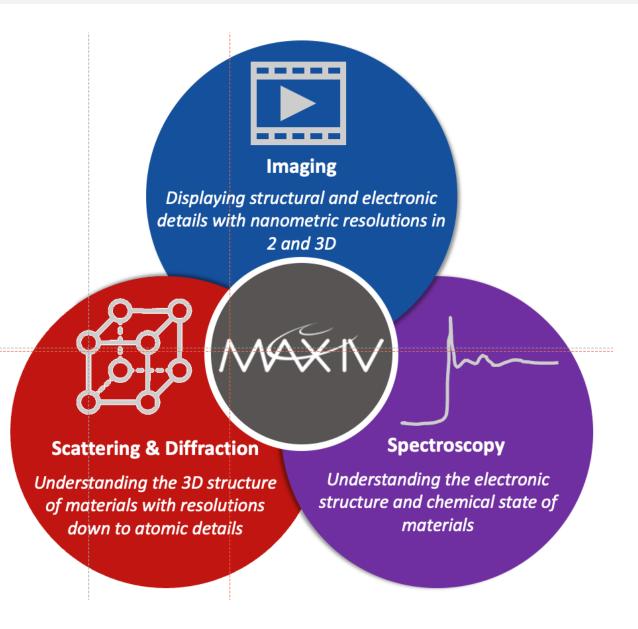




This is MAX IV !



Providing modern X-ray tools to support the current and future research needs of the user community.





Research

Industry Opportunities Graduate School

Extending our materials science beamlines portfolio

Wallenberg Initiative Materials Science for Sustainability

Enabling sustainable technologies with positive impact on our society by understanding, creating, and controlling complex materials

(A)



MAX IV and Wallenberg Initiative Materials Science for Sustainability (WISE) Summary of Existing Capabilities 2023-04-17



Download the document from <u>maxiv.se</u> or via the QR code:



Imaging beamline A hard X-ray tomography beam

A hard X-ray tomography beamline dedicated to microstructure characterization and 4D imaging of materials.

Diffraction beamline

A high-throughput, flexible diffraction beamline for fast and time-resolved structural characterization of surfaces, powders, and crystals.

Spectroscopy beamline

A tender-to-hard X-ray spectroscopy beamline for *in situ* and *operando* characterization of surfaces and buried interfaces under realistic conditions.

NOVEMBER 2023



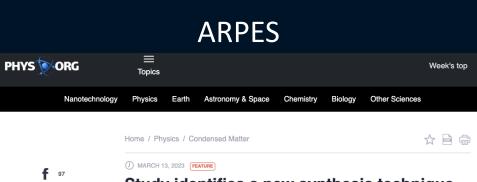
WISE funds the Conceptual Design Reports of three new beamlines supporting materials science for sustainability.





Spectroscopy

Angular Resolved PhotoElectron Spectroscopy



in Share

BLOCH

Study identifies a new synthesis technique to attain monolayer honeycomb SiC

(a) (e^) - Er (eV) (e) TaC(111) + SiC monolayer (d) SiC monolayer (f) Measured 2-E - E_F (eV) (eV) (ve) щ ш σ. -6 -6

(b) TaC(111) + SiC monolayer, DFT

(c) Measured

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FIG. 3. (a) Schematic depiction of the honeycomb SiC structure. (b) Slab DFT band structure calculation for this structure along the $\overline{\Gamma} \cdot \overline{K} \cdot \overline{M}$ path. The surface-projected TaC bulk band structure is indicated by the shaded grey regions. (c) ARPES spectrum at $h\nu = 67 \text{ eV}, T = 80 \text{ K}$. (d) DFT band structure of a planar, freestanding SiC monolayer along the $\overline{M} \cdot \overline{\Gamma} \cdot \overline{K}$ path. (e) The same calculation for SiC atop TaC(111) as shown in (b), but sampling only the topmost two atomic layers and resolved into atomic character. (f) Corresponding experimental spectra, presented as a second derivative image. The $\overline{\Gamma} \cdot \overline{M}$ slice is acquired from the second Brillouin zone with $h\nu = 138 \text{ eV}$ while the $\overline{\Gamma} \cdot \overline{K}$ slice is with $h\nu = 44 \text{ eV}$, both at T = 80 K.

M

-8

-10

Si + C

-8

-10

M

C. M. Polley et al, Bottom-Up Growth of Monolayer Honeycomb SiC, *Physical Review Letters* **130**, 076203 (2023)